Searcn Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/762,031	YUEH
Examiner	Art Unit
John S. Chu	1752

SEARCHED			
Class	Subclass	Date	Examiner
430	168	8(5000	<i>y</i> -
430	190	1	
430	326		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEAR)		<b>(</b> )
	DATE	EXMR
EAST SEARCH updated	8(5042	gr-